



Dr. In-Yong Park
(KRISS, Korea)

[Professional Experience]

- 2023.03 ~ Present: Chungnam National University, GRaduate school of Analytical Science and Technology, Adjunct Professor
- 2021.10 ~ Present: ISO/TC 202/SC4 Scanning electron microscopy expert member
- 2019.03 ~ Present: University of Science and Technology, Adjunct Professor
- 2012.05 ~ Present: Korea Research Institute of Standards and Science, Principal researcher

[Education]

- 2011.08 Doctor degree: KAIST (Korea Advanced Institute of Science and Technology), Dept. of Mechanical engineering
- 2007.02 Master degree: GIST (Gwangju Institute of Science and Technology), Dept. of Mechatronics
- 2005.02 Bachelor degree: Chung-Ang University, Dept. of Mechanical engineering

[Research Area]

- Development of a high-brightness charged particle source and electron microscope
- Semiconductor measurement and inspection methodology using a scanning electron microscope
- Generation of X-ray and extreme ultraviolet light sources

[Recent Publication]

- D.-J. Yun, *et al.* "Three-Dimensional Reconstruction of Serial Block-Face Scanning Electron Microscopy using Semantic Segmentation based on Semi-Supervised Deep Learning", *Microscopy and Microanalysis*, **31**, oza047 (2025)
- J. Hwang, *et al.* "A cylindrical lens spectrometer with parallel detection for reflection electron energy loss spectroscopy", *Microscopy and Microanalysis*, **31**, ozae118 (2025)
- H. R. Lee, *et al.* "Exploring the Potential of a Thermionic LaB6 Virtual Source Mode Electron Gun for a High Angular Current Density and a Narrow Energy Distribution", *Microscopy and Microanalysis*, **29**, 2004–2013 (2023)